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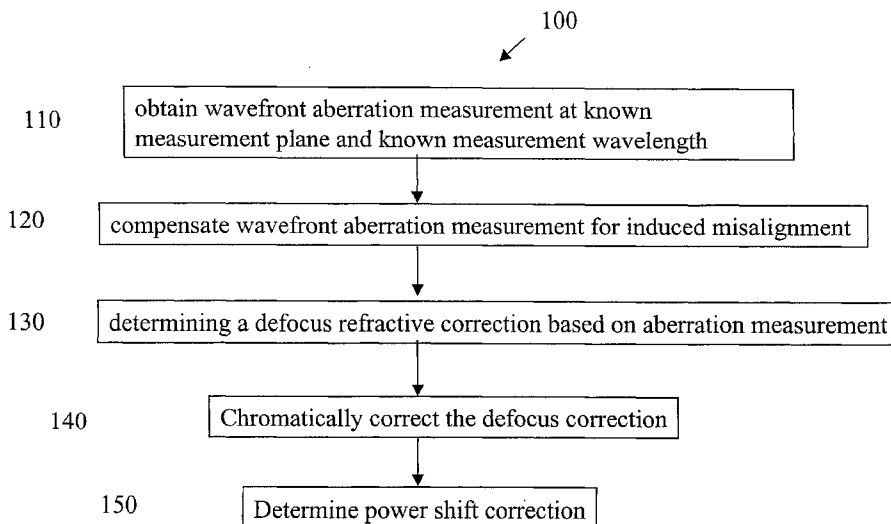
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(54) Title: WAVEFRONT-GENERATED CUSTOM OPHTHALMIC SURFACES



(57) Abstract: An embodiment of the invention is directed to a method for determining an anterior or posterior surface parameter of an ophthalmic correcting surface (e.g., custom contact lens "CCL," customized IOL, custom inlay, customized corneal surface) from a wavefront aberration measurement of an eye. A preferred embodiment relates to determining an anterior surface parameter of a dry, CCL designed to operate at 555nm. An algorithm sets forth the method comprising misalignment correction, chromatic aberration correction, and power shift correction due to differences between aberration measurement wavelength and peak vision wavelength, and differences between aberration measurement location and aberration correction location. A device readable medium is the preferable vehicle for the algorithm.

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